

Identification Of Defects In Semiconductors. Semiconductors And Semimetals, Volume 51a.

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This volume has contributions on Advanced Characterization Techniques with a focus on defect identification. The combination of beam techniques with electrical and optical characterization has not been discussed elsewhere. EAN/ISBN : 9780080864488 Publisher(s): Elsevier Science & Technology, Academic Press Format: ePub/PDF Author(s): Willardson, Michael Robert K. - Weber, Eicke R. - Stavola

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